

CLEAN VERSION



Abstract of the Disclosure

The I/O compression test circuit performs tests on global I/O lines divided into groups after failure occurs, thereby improving repair efficiency. The configuration of the test circuit is simplified by using a reset circuit, reducing the delay time, and thereby decreasing test time. Additionally, two strobe signals enable the I/O compression test circuit to perform a stable operation.

In the Abstract:

Please substitute the following replacement Abstract, submitted herewith as Attachment A. All deleted material is shown by strike-through effects. All added text is underlined. No new matter is added.